

# Appendix A

## List of Publications

### A.1 Journal Papers

1. **Rakesh Kumar** and Amrita Chaturvedi. "Software Bug Prediction Using Reward-Based Weighted Majority Voting Ensemble Technique." **IEEE Transactions on Reliability**, vol. 73.1, pp. 726-740  
doi: 10.1109/TR.2023.3295598. (2023). (Published) (**SCI/SCIE, IF: 5.9**)
2. **Rakesh Kumar**, Amrita Chaturvedi, and Lakshmanan Kailasam. "An unsupervised software fault prediction approach using threshold derivation." **IEEE Transactions on Reliability**, vol. 71.2, pp. 911-932.  
(doi: 10.1109/TR.2022.3151125).(2022) (Published) (**SCI/SCIE, IF: 5.9**)
3. **Rakesh Kumar** and Amrita Chaturvedi: An Unsupervised Software Bug Count Prediction Model Based on Selected Software Metrics, **Expert Systems with Applications**, Elsevier (Under Review), (**SCI/SCIE, IF: 8.5**)
4. **Rakesh Kumar** and Amrita Chaturvedi: An Unsupervised Software Defect Prediction System in Functional Paradigm, **Expert Systems with Applications**, Elsevier, (Under Review) (**SCI/SCIE, IF: 8.5**)

## A.2 Conference Papers

1. **Rakesh Kumar** and Amrita Chaturvedi. "Software Fault Prediction Using Data Mining Techniques on Software Metrics." (Proceedings of International Conference on Machine Learning and Big Data Analytics (**ICMLBDA**) 2021), (**IIT Patna**). **Springer** International Publishing, 2022.  
[https://doi.org/10.1007/978-3-030-82469-3\\_27](https://doi.org/10.1007/978-3-030-82469-3_27)
2. **Rakesh Kumar** and Amrita Chaturvedi. "A Framework for Software Defect Prediction Using Optimal Hyper-Parameters of Deep Neural Network." In: The 29<sup>th</sup> International Conference on Neural Information Processing (**29<sup>th</sup> ICONIP 2022**), **IIT Indore**, India, **Springer** International Publishing, 2022.
3. **Rakesh Kumar** and Amrita Chaturvedi. "Software Bug Count Prediction Model Based on Software Source Code," In: 14th International Conference on Computing Communication and Networking Technologies (**14<sup>th</sup> ICCCNT**), **IIT Delhi**, India, 2023, pp. 1-6, published in **IEEE** Digital Library Xplore®<sup>®</sup>, doi: 10.1109/ICCCNT56998.2023.10307457.

# Appendix B

## Sample Datasets and Other Results

The datasets used in the chapters are from open-source projects and may not be generalized well to proprietary or industrial projects with different characteristics. Therefore, we conducted an experiment using eight additional datasets: Eclipse [226, 243, 244], which has three versions (2.0, 2.1, 3.0), and Android [183, 245], which has five versions (2013\_1, 2013\_2, 2013\_3, 2014\_1, 2014\_2). The Eclipse and Android projects were chosen due to their alignment with industrial/commercial systems in terms of size and complexity, following industry-standard development processes. Each Eclipse dataset<sup>1</sup> release contains file name, pre-release and post-release bugs,

<sup>1</sup><https://www.st.cs.uni-saarland.de/softevo/>

TABLE B.1: Sample bug dataset (First 20 modules of Tomcat project)

name	version	name	wmc	dit	noc	cbo	rfc	lcom	ca	ce	npm	lcom3	loc	dam	mosa	mfa	cam	ic	cbm	ame	max.ec	avg.ec	bug
Tomcat	6.0.389418	org.apache.coyote.http11.filters.VoidOutputFilter	8.00	1.00	0.00	6.00	14.00	26.00	2.00	0.00	7.00	1.00	39.00	1.00	2.00	0.00	0.39	0.00	0.00	3.50	1.00	0.75	0
Tomcat	6.0.389418	org.apache.el.parser.AstGreaterThanOr	2.00	4.00	0.00	4.00	5.00	1.00	1.00	0.00	2.00	2.00	36.00	0.00	0.00	0.98	0.67	1.00	1.00	17.00	1.00	0.50	0
Tomcat	6.0.389418	org.apache.coyote.Request	56.00	1.00	0.00	49.00	89.00	1310.00	40.00	0.00	56.00	0.96	583.00	1.00	24.00	0.00	0.14	0.00	0.00	8.82	5.00	1.20	0
Tomcat	6.0.389418	javax.el.MethodNotFoundException	4.00	5.00	1.00	0.00	8.00	6.00	0.00	0.00	4.00	2.00	20.00	0.00	0.00	1.00	0.67	0.00	0.00	4.00	0.00	0.00	0
Tomcat	6.0.389418	org.apache.naming.EjbRef	3.00	2.00	0.00	3.00	8.00	3.00	3.00	0.00	3.00	1.50	73.00	0.00	0.00	0.94	0.83	0.00	0.00	22.00	3.00	1.00	0
Tomcat	6.0.389418	org.apache.jasper.compiler.Compiler	16.00	1.00	2.00	38.00	91.00	58.00	23.00	0.00	13.00	0.78	717.00	0.89	7.00	0.00	0.28	0.00	0.00	43.25	15.00	1.94	1
Tomcat	6.0.389418	javax.servlet.ServletContextAttributeListener	3.00	1.00	0.00	0.00	3.00	3.00	0.00	0.00	3.00	2.00	3.00	0.00	0.00	0.00	1.00	0.00	0.00	0.00	1.00	1.00	0
Tomcat	6.0.389418	org.apache.el.MethodExpressionLiteral	10.00	3.00	0.00	3.00	24.00	3.00	1.00	0.00	10.00	0.48	114.00	1.00	0.00	0.43	0.21	1.00	1.00	10.10	3.00	1.00	0
Tomcat	6.0.389418	org.apache.naming.ResourceEnvRef	3.00	2.00	0.00	2.00	7.00	3.00	2.00	0.00	3.00	1.50	30.00	0.00	0.00	0.94	0.83	0.00	1.00	8.67	3.00	1.00	0
Tomcat	6.0.389418	org.apache.catalina.mbeans.StandardServerMBean	3.00	2.00	0.00	5.00	8.00	3.00	0.00	0.00	2.00	1.00	27.00	1.00	0.00	0.98	1.00	0.00	0.00	7.67	1.00	0.33	0
Tomcat	6.0.389418	org.apache.naming.NamingService	11.00	2.00	0.00	1.00	25.00	35.00	0.00	0.00	11.00	0.65	283.00	1.00	0.00	0.41	0.32	0.00	0.00	24.36	2.00	1.18	0
Tomcat	6.0.389418	org.apache.catalina.startup.WebRuleSet	4.00	2.00	0.00	12.00	22.00	2.00	1.00	0.00	4.00	0.58	1700.00	1.00	3.00	0.50	0.50	1.00	1.00	423.00	1.00	0.50	2
Tomcat	6.0.389418	org.apache.naming.NameNotFoundException	6.00	5.00	0.00	1.00	7.00	15.00	1.00	0.00	6.00	2.00	14.00	0.00	0.00	0.86	0.46	1.00	1.00	1.33	1.00	0.83	0
Tomcat	6.0.389418	javax.servlet.jsp.tagext.JspTag	0.00	1.00	0.00	0.00	0.00	0.00	0.00	0.00	0.00	2.00	0.00	0.00	0.00	0.00	0.00	0.00	0.00	0.00	0.00	0.00	0
Tomcat	6.0.389418	org.apache.tomcat.util.net.jsse.JSSE13SocketFactory	6.00	3.00	0.00	8.00	33.00	3.00	1.00	0.00	1.00	0.40	177.00	1.00	0.00	0.83	0.40	1.00	6.00	28.33	1.00	0.83	0
Tomcat	6.0.389418	org.apache.catalina.realm.MemoryRuleSet	3.00	2.00	0.00	6.00	9.00	1.00	2.00	0.00	3.00	0.00	35.00	1.00	0.00	0.67	0.56	1.00	1.00	10.33	1.00	0.33	0
Tomcat	6.0.389418	org.apache.tomcat.jni.Pool	14.00	1.00	0.00	3.00	15.00	91.00	3.00	0.00	14.00	2.00	17.00	0.00	0.00	0.00	0.29	0.00	0.00	0.21	1.00	0.93	0
Tomcat	6.0.389418	javax.servlet.jsp.JspEngineInfo	2.00	1.00	1.00	0.00	3.00	1.00	0.00	0.00	2.00	2.00	5.00	0.00	0.00	0.00	1.00	0.00	0.00	1.50	1.00	0.50	0
Tomcat	6.0.389418	org.apache.jk.common.HandlerRequest	22.00	2.00	0.00	20.00	145.00	127.00	0.00	0.00	15.00	0.87	1226.00	0.86	1.00	0.55	0.31	2.00	2.00	54.00	10.00	2.32	0

TABLE B.2: Eclipse and Android bug datasets descriptions

Group	Datasets	#Metrics	#Module	#Bug	Bug%
Eclipse	Eclipse-2.0	199	6729	975	14.49
	Eclipse-2.1	199	7888	854	10.83
	Eclipse-3.0	199	10593	1568	14.80
	A_2013.1	107	73	35	47.95
Android	A_2013.2	107	98	22	22.45
	A_2013.3	107	109	2	1.83
	A_2014.1	107	116	8	6.90
	A_2014.2	107	119	2	1.68

complexity metrics, and abstract syntax tree metrics, including number of nodes, types, and frequency. Android datasets<sup>2</sup> is extracted from Android-Universal-Image-Loader software projects<sup>3</sup>. Eclipse and Android datasets descriptions in terms of number of metrics, modules, bugs, and bug% is given in Table B.2. The experimental results of the SBP/SBCV prediction models presented in Chapters 3, 4, and 5 are shown in Tables B.3, B.4, and B.5, respectively.

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<sup>2</sup><https://www.inf.u-szeged.hu/~ferenc/papers/GitHubBugDataSet/GitHubBugDataSet.zip>

<sup>3</sup><https://github.com/nostra13/Android-Universal-Image-Loader>

TABLE B.3: Performance of SBP techniques (Chapter 3) over Eclipse and Android datasets in terms of accuracy, FM, MCC

Projects	Accuracy (%)										F-measure										MCC									
	NB	SVM	KNN	RF	C50	SMV	WMV	NB	SVM	KNN	RF	C50	SMV	WMV	NB	SVM	KNN	RF	C50	SMV	WMV	NB	SVM	KNN	RF	C50	SMV	WMV		
Eclipse-2.0	95.96	95.70	79.44	95.75	95.98	96.78	97.78	0.99	0.98	0.85	0.98	0.98	0.98	0.98	0.88	0.87	0.58	0.87	0.87	0.87	0.87	0.88	0.87	0.58	0.87	0.87	0.87	0.90		
Eclipse-2.1	96.46	94.89	78.15	96.67	95.99	96.67	97.67	0.98	0.97	0.84	0.97	0.96	0.97	0.97	0.87	0.86	0.56	0.86	0.86	0.86	0.86	0.87	0.86	0.56	0.86	0.86	0.86	0.89		
Eclipse-3.0	95.90	95.63	78.76	95.68	95.99	96.85	97.85	0.98	0.98	0.84	0.97	0.98	0.98	0.99	0.86	0.87	0.57	0.88	0.88	0.88	0.88	0.86	0.87	0.57	0.88	0.88	0.88	0.90		
AVG	96.11	95.41	78.78	96.04	95.99	96.77	<b>97.77</b>	<b>0.98</b>	0.97	0.84	0.97	0.97	<b>0.98</b>	<b>0.98</b>	0.87	0.87	0.57	0.87	0.87	0.87	0.87	0.87	0.87	0.57	0.87	0.87	0.87	<b>0.90</b>		
A_2013.1	86.34	76.46	67.39	77.89	66.83	86.30	87.93	0.89	0.78	0.62	0.82	0.73	0.88	0.90	0.73	0.59	0.47	0.65	0.51	0.67	0.74	0.73	0.59	0.47	0.65	0.51	0.67	0.74		
A_2013.2	95.78	79.22	63.65	95.07	89.04	95.92	95.92	0.95	0.79	0.71	0.95	0.89	0.96	0.96	0.92	0.67	0.43	0.92	0.80	0.88	0.92	0.92	0.67	0.43	0.92	0.80	0.88	0.92		
A_2013.3	99.55	99.64	76.19	99.90	96.89	99.91	99.99	0.99	1.00	0.65	1.00	0.97	1.00	1.00	1.00	1.00	0.65	1.00	0.98	1.00	1.00	1.00	1.00	0.65	1.00	0.98	1.00	1.00		
A_2014.1	97.39	88.21	77.08	98.98	98.09	99.14	99.14	0.97	0.88	0.67	0.99	0.98	0.99	0.99	0.98	0.78	0.61	1.00	0.98	0.95	0.98	0.98	0.78	0.61	1.00	0.98	0.95	0.98		
A_2014.2	99.99	99.17	88.42	98.26	97.30	99.16	99.16	0.99	0.99	0.88	0.98	0.97	0.99	0.99	0.98	0.98	0.80	0.98	0.98	0.98	0.98	0.98	0.98	0.80	0.98	0.98	0.98	0.98		
AVG	95.81	88.54	74.54	94.04	89.63	96.10	<b>96.43</b>	0.96	0.89	0.70	0.95	0.91	0.96	<b>0.97</b>	0.92	0.80	0.59	0.91	0.85	0.90	<b>0.93</b>	0.92	0.80	0.59	0.91	0.85	0.90	<b>0.93</b>		

TABLE B.4: Performance of different SBP techniques (Chapter 4) over Eclipse datasets (larger datasets)

Projects Name	Accuracy %													
	Supervised Methods					Unsupervised Methods				Threshold Based Methods				
	NB	SVM	KNN	RF	C50	KMS	NGC	MBC	HC	CLAMI	CLAMI+	ACL	TCL	TCLP
Eclipse-2.0	85.05	85.43	85.09	88.33	87.84	86.65	86.75	76.48	85.92	50.36	52.40	61.49	84.80	86.23
Eclipse-2.1	87.11	87.30	86.20	90.00	88.56	88.17	87.26	73.73	86.38	42.77	44.98	54.04	84.74	87.75
Eclipse-3.0	84.18	85.40	85.87	86.18	85.50	85.70	82.30	74.73	85.30	54.72	57.54	62.31	83.17	86.65
AVG	85.45	86.04	85.72	<b>88.17</b>	87.30	86.84	85.44	74.98	85.86	49.28	51.64	59.28	84.23	86.88

  

Projects Name	F-measure													
	Supervised Methods					Unsupervised Methods				Threshold Based Methods				
	NB	SVM	KNN	RF	C50	KMS	NGC	MBC	HC	CLAMI	CLAMI+	ACL	TCL	TCLP
Eclipse-2.0	0.91	0.91	0.90	0.92	0.92	0.32	0.39	0.78	0.80	0.60	0.67	0.72	0.91	0.92
Eclipse-2.1	0.91	0.93	0.92	0.92	0.92	0.28	0.43	0.83	0.84	0.54	0.73	0.74	0.91	0.92
Eclipse-3.0	0.90	0.90	0.91	0.91	0.91	0.26	0.40	0.76	0.82	0.65	0.65	0.73	0.90	0.91
AVG	0.91	0.91	0.91	<b>0.92</b>	<b>0.92</b>	0.29	0.41	0.79	0.82	0.60	0.69	0.73	0.91	<b>0.92</b>

  

Projects Name	MCC													
	Supervised Methods					Unsupervised Methods				Threshold Based Methods				
	NB	SVM	KNN	RF	C50	KMS	NGC	MBC	HC	CLAMI	CLAMI+	ACL	TCL	TCLP
Eclipse-2.0	0.32	0.32	0.29	0.42	0.38	0.31	0.30	0.26	0.27	0.26	0.27	0.31	0.33	0.34
Eclipse-2.1	0.25	0.26	0.30	0.29	0.33	0.25	0.24	0.24	0.24	0.15	0.19	0.24	0.24	0.26
Eclipse-3.0	0.27	0.28	0.28	0.27	0.27	0.25	0.28	0.26	0.26	0.25	0.27	0.25	0.28	0.30
AVG	0.28	0.29	0.29	<b>0.33</b>	<b>0.33</b>	0.27	0.27	0.26	0.26	0.22	0.25	0.27	0.29	0.29

TABLE B.5: Results of MTB/MTBP and 8 ML models (Chapter 5) over Eclipse and Android DSs

Datasets	Mean Absolute Error (MAE)								Mean Relative Error (MRE)								Prediction at level $\lambda=0.3$ error (Pred( $\lambda$ )-Error)													
	MTB	MTBP	LM	MLP	GA	DTR	SVR	KNN	BRR	NBR	MTB	MTBP	LM	MLP	GA	DTR	SVR	KNN	BRR	NBR	MTB	MTBP	LM	MLP	GA	DTR	SVR	KNN	BRR	NBR
Eclipse-2.0	0.19	0.16	0.27	0.24	0.26	0.27	0.20	0.28	0.29	0.28	0.10	0.06	0.18	0.11	0.17	0.18	0.09	0.18	0.19	0.18	0.13	0.10	0.20	0.10	0.27	0.27	0.10	0.24	0.18	0.20
Eclipse-2.1	0.36	0.32	0.43	0.43	0.46	0.41	0.34	0.42	0.45	0.43	0.21	0.14	0.31	0.41	0.33	0.29	0.16	0.21	0.31	0.31	0.31	0.26	0.45	0.66	0.26	0.29	0.21	0.26	0.47	0.45
Eclipse-3.0	0.21	0.11	0.19	0.18	0.18	0.18	0.14	0.18	0.19	0.19	0.16	0.05	0.13	0.26	0.12	0.13	0.07	0.11	0.12	0.13	0.19	0.09	0.13	0.08	0.17	0.09	0.08	0.13	0.13	0.13
A-2013.1	0.53	0.44	0.61	0.63	0.69	0.62	0.55	0.63	0.66	0.60	0.33	0.18	0.38	0.24	0.40	0.43	0.21	0.36	0.42	0.38	0.40	0.29	0.51	0.38	0.96	0.82	0.27	0.56	0.86	0.51
A-2013.2	0.36	0.24	0.38	0.34	0.35	0.34	0.31	0.32	0.34	0.31	0.29	0.14	0.22	0.21	0.19	0.14	0.11	0.21	0.22	0.22	0.32	0.21	0.35	0.22	0.12	0.09	0.13	0.23	0.33	0.35
A-2013.3	0.36	0.08	0.06	0.06	0.04	0.04	0.03	0.04	0.04	0.05	0.35	0.07	0.03	0.03	0.03	0.03	0.02	0.02	0.03	0.03	0.36	0.08	0.02	0.02	0.02	0.02	0.02	0.02	0.02	0.02
A-2014.1	0.42	0.20	0.14	0.08	0.15	0.14	0.10	0.13	0.13	0.13	0.40	0.17	0.09	0.03	0.09	0.09	0.05	0.09	0.09	0.09	0.37	0.19	0.06	0.06	0.06	0.06	0.06	0.09	0.06	0.06
A-2014.2	0.33	0.11	0.06	0.04	0.03	0.02	0.03	0.03	0.03	0.05	0.32	0.11	0.04	0.01	0.02	0.02	0.02	0.02	0.02	0.03	0.29	0.10	0.02	0.02	0.02	0.02	0.02	0.02	0.02	0.02
AVG	0.34	<b>0.21</b>	0.27	0.25	0.27	0.25	<b>0.21</b>	0.25	0.27	0.26	0.27	0.11	0.17	0.16	0.17	0.16	<b>0.09</b>	0.15	0.18	0.17	0.35	0.18	0.19	0.14	0.24	0.20	<b>0.10</b>	0.18	0.26	0.19

TABLE B.6: Effect size using CohenD between WMV and others models (Chapter 3)

WMV	NB	SVM	KNN	RF	C50	SMV
Accuracy	0.75	1.60	2.15	0.42	0.66	0.14
FM	0.82	1.67	1.90	0.47	0.67	0.15
MCC	0.07	0.30	0.57	0.05	0.07	0.16

TABLE B.7: Effect size using CohenD between TCLP and others models (Chapter 4)

TCLP	NB	SVM	KNN	RF	C50	KMS	NGC	MBC	HC	CLA	CLAMI	CLAMI+	ACL	TCL
Accuracy	0.49	0.54	0.48	0.58	0.56	0.02	0.00	0.98	0.04	1.98	1.92	1.95	1.82	0.02
FM	0.28	0.25	0.12	0.27	0.24	0.92	1.31	1.15	0.11	2.04	1.93	1.89	1.76	0.01
MCC	0.81	0.22	0.14	0.65	0.70	0.68	0.48	0.51	0.95	0.23	0.15	0.06	0.05	0.04

TABLE B.8: Effect size using CohenD between UMV and others models (Chapter 6)

UMV	CLAMI	CLAMI+	ACL	TCLP	SQRT	CBRT	KMS	NGC	MBC	HC	NB	SVM	KNN	RF	C50
Accuracy	2.06	4.82	0.64	0.71	0.81	0.88	0.83	0.64	1.82	1.67	0.16	0.93	0.32	2.30	1.51
FM	2.12	4.80	0.83	0.94	1.01	1.01	2.38	0.79	1.64	1.70	0.31	0.94	0.19	1.84	1.00
MCC	1.93	3.67	0.56	0.25	0.40	0.23	0.69	0.45	0.94	1.72	1.13	1.47	0.78	2.48	2.10

TABLE B.9: Cross-version (Training on previous version and testing on current version) performance of different SBP models (Chapter 3)

Datasets	Accuracy (%)										F-measure										MCC									
	Testing	NB	SVM	KNN	RF	C50	SMV5	WMV5	NB	SVM	KNN	RF	C50	SMV5	WMV5	NB	SVM	KNN	RF	C50	SMV5	WMV5	NB	SVM	KNN	RF	C50	SMV5	WMV5	
Ant-1.6	Ant-1.7	79.87	78.12	80.13	77.72	79.33	79.60	81.17	0.87	0.86	0.88	0.85	0.87	0.87	0.89	0.43	0.35	0.39	0.42	0.42	0.39	0.39	0.43	0.35	0.39	0.42	0.42	0.39	0.39	
Camel-1.4	Camel-1.6	77.93	78.03	79.90	80.62	80.93	79.59	80.53	0.87	0.87	0.89	0.89	0.89	0.88	0.89	0.16	0.12	0.15	0.20	0.20	0.17	0.21	0.16	0.12	0.15	0.20	0.20	0.17	0.21	
Forrest-0.7	Forrest-0.8	59.38	65.63	93.75	81.25	68.75	68.75	73.10	0.72	0.78	0.97	0.89	0.80	0.80	0.94	0.27	0.31	0.00	0.45	0.45	0.33	0.41	0.27	0.31	0.00	0.45	0.45	0.33	0.41	
Ivy-1.4	Ivy-2.0	89.49	87.78	88.92	89.20	87.50	88.92	92.93	0.94	0.93	0.94	0.94	0.93	0.94	0.94	0.39	0.25	0.26	0.39	0.39	0.28	0.39	0.39	0.25	0.26	0.39	0.39	0.28	0.39	
Jedit-4.2	Jedit-4.3	91.67	91.46	93.50	90.65	91.67	92.68	90.19	0.96	0.96	0.97	0.95	0.96	0.96	0.90	0.16	0.16	0.20	0.15	0.15	0.38	0.22	0.16	0.16	0.20	0.15	0.15	0.38	0.22	
Log4j-1.1	Log4j-1.2	32.68	38.05	25.37	29.76	25.37	29.76	32.66	0.18	0.17	0.16	0.17	0.15	0.17	0.20	0.13	0.09	0.09	0.12	0.12	0.12	0.12	0.13	0.09	0.09	0.12	0.12	0.12	0.12	
Lucene-2.0	Lucene-2.4	54.71	59.12	47.94	54.41	53.53	53.53	58.26	0.45	0.52	0.27	0.44	0.40	0.61	0.61	0.25	0.33	0.17	0.24	0.24	0.24	0.32	0.25	0.33	0.17	0.24	0.24	0.24	0.32	
Poi-2.5	Poi-3.0	58.14	51.36	42.53	53.62	42.76	53.85	59.39	0.54	0.44	0.21	0.45	0.23	0.60	0.61	0.34	0.20	0.13	0.29	0.29	0.29	0.29	0.34	0.20	0.13	0.29	0.29	0.29	0.29	
Prop-5	Prop-6	79.24	79.39	89.09	81.97	83.64	82.58	92.24	0.88	0.88	0.94	0.90	0.91	0.90	0.93	0.18	0.08	0.22	0.17	0.17	0.15	0.20	0.18	0.08	0.22	0.17	0.17	0.15	0.20	
Synapse-1.1	Synapse-1.2	71.48	65.23	71.88	72.27	70.31	71.48	73.42	0.79	0.73	0.80	0.80	0.79	0.79	0.72	0.34	0.24	0.33	0.35	0.35	0.34	0.36	0.34	0.24	0.33	0.35	0.35	0.34	0.36	
Velocity-1.5	Velocity-1.6	67.69	65.94	65.50	67.25	66.81	67.69	69.39	0.37	0.30	0.22	0.29	0.22	0.79	0.78	0.20	0.14	0.10	0.17	0.17	0.18	0.19	0.20	0.14	0.10	0.17	0.17	0.18	0.19	
Xalan-2.6	Xalan-2.7	21.67	19.14	18.37	26.07	25.52	20.24	28.66	0.03	0.03	0.03	0.03	0.03	0.03	0.03	0.06	0.05	0.05	0.06	0.06	0.05	0.06	0.06	0.05	0.05	0.06	0.05	0.06	0.06	
Xerces-1.3	Xerces-1.4	36.73	33.67	30.61	38.27	34.18	34.01	39.72	0.44	0.43	0.41	0.45	0.44	0.45	0.93	0.19	0.14	0.06	0.21	0.21	0.15	0.22	0.19	0.14	0.06	0.21	0.21	0.15	0.22	
Average		63.13	62.53	63.65	64.85	62.33	63.28	<b>67.05</b>	0.62	0.61	0.59	0.62	0.59	0.68	<b>0.72</b>	0.24	0.19	0.16	0.25	0.25	0.24	<b>0.26</b>	0.24	0.19	0.16	0.25	0.25	0.24	<b>0.26</b>	

## B.1 Distinguishing properties of functional paradigms

Functional programming is a paradigm that significantly emphasizes the utilization of pure functions and immutable data to craft robust and predictable software. This paradigm is distinguished by several key properties [246, 247].

- **First-Class and Higher-Order Functions:** Functions in functional programming are treated as first-class citizens. This means they can be assigned to variables, passed as arguments, and returned by other functions, enhancing flexibility and power through the use of higher-order functions. These can accept other functions as inputs or return them as outputs, facilitating complex functional constructs.
- **Pure Functions:** Functions within this paradigm are inherently pure, avoiding any side effects such as modifying global or static variables. They consistently produce the same output for the same set of inputs, thereby enhancing the reliability and predictability of code behavior.
- **Immutability:** In functional programming, data is immutable, meaning once it is created, it cannot be altered. This approach avoids the complications associated with shared mutable state and enhances code safety and predictability.
- **Referential Transparency:** An expression exhibits referential transparency if it can be substituted with its value without altering the behavior of the program. This is enabled by the use of pure functions and immutable data, allowing compilers to optimize more easily and enhance predictability.
- **Recursion:** Given the immutable nature of data, functional programming often relies on recursion to handle loops or repetitive operations. Compilers for functional languages typically optimize tail recursion to improve the performance of these recursive functions.
- **Function Composition:** This paradigm often employs the composition of simpler functions to build more complex functionalities. Function composition

fosters modularity and reusability, making the code simpler to maintain and understand.

- **Lazy Evaluation:** Some functional programming languages implement lazy evaluation, delaying the computation of expressions until their values are needed. This technique can significantly boost performance, particularly when dealing with potentially infinite data structures or operations.
- **Type Systems:** Many functional languages are equipped with robust, static type systems that include features like type inference. These systems help catch errors at compile time, enhancing code safety and performance while minimizing the burden of excessive type annotations.



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